

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10575425	PROUET ET AL.
	Examiner	Art Unit
	JOHN W POOS	4125

SEARCHED			
Class	Subclass	Date	Examiner
327	103	11/29/2007	JP
323	315	12/3/2007	JP

SEARCH NOTES			
Search Notes	Date	Examiner	
terms used to constrain subclasses above: chip, different sized transistors, transconductance, differential input voltage	11/29/2007	JP	
Inventor search in EAST and eDAN	12/3/2007	JP	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner